

Chipsmall Limited consists of a professional team with an average of over 10 year of expertise in the distribution of electronic components. Based in Hongkong, we have already established firm and mutual-benefit business relationships with customers from, Europe, America and south Asia, supplying obsolete and hard-to-find components to meet their specific needs.

With the principle of "Quality Parts, Customers Priority, Honest Operation, and Considerate Service", our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip, ALPS, ROHM, Xilinx, Pulse, ON, Everlight and Freescale. Main products comprise IC, Modules, Potentiometer, IC Socket, Relay, Connector. Our parts cover such applications as commercial, industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



### Contact us

Tel: +86-755-8981 8866 Fax: +86-755-8427 6832

Email & Skype: info@chipsmall.com Web: www.chipsmall.com

Address: A1208, Overseas Decoration Building, #122 Zhenhua RD., Futian, Shenzhen, China







## 6N138

#### **■** Features

1. High current transfer ratio ( CTR : MIN. 300% at  $I_F$ =1.6mA )

2. High speed response

(  $t_{PHL}1$  : TYP.  $2\mu s$  at  $R_L$ = $2.2k\Omega$  )

3. Instantaneous common mode rejection voltage

(  $CM_H$ : TYP. 500V/ $\mu s$  ) 4. TTL compatible output

5. Recognized by UL, file No. E64380

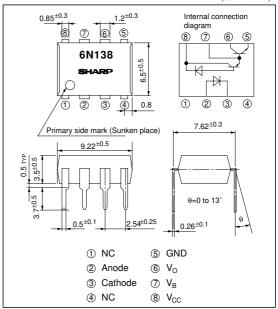
#### ■ Applications

- 1. Interfaces for computer peripherals
- 2. Measuring instruments, Control equipment
- 3. Telephone sets
- 4. Signal transmission between circuits of different potentials and impedances

# High Sensitivity, High Speed \*OPIC Photocoupler

#### **■** Outline Dimensions

(Unit:mm)



<sup>\* &</sup>quot;OPIC" (Optical IC) is a trademark of the SHARP Corporation. An OPIC consists of a light-detecting element and signal-processing circuit integrated onto a single chip.

#### ■ Absolute Maximum Ratings

(Ta=25°C) Unit

Parameter		Symbol	Rating	Unit	
Input	Forward current	$I_{F}$	20	mA	
	*1 Peak forward current	$I_F$	40	mA	
	*2 Peak transient forward current	$I_{FM}$	1	A	
	Reverse voltage	V <sub>R</sub>	5	V	
	Power dissipation	P	35	mW	
Output	Supply voltage	Vcc	-0.5 to +7	V	
	Output voltage	Vo	-0.5 to +7	V	
	Emitter-base reverse withstand voltage (Pin 5 to 7)	$V_{\rm EBO}$	0.5	V	
	*3 Average output current	Io	60	mA	
	Power dissipation	Po	100	mW	
	*4 Isolation voltage	V <sub>iso</sub> (rms)	2.5	kV	
Operating temperature		Topr	0 to +70	°C	
	Storage temperature	T <sub>stg</sub>	-55 to +125	°C	
*5 Soldering temperature		T <sub>sol</sub>	260	°C	

<sup>\*1 50%</sup> duty cycle, Pulse width=1ms

<sup>\*2</sup> Pulse width≤1µs, 300pulse/s

<sup>\*3</sup> Decreases at the rate of 0.7mA/°C if the external temperature is 25°C or more.

<sup>\*4 40</sup> to 60% RH, AC for 1 minute

<sup>\*5</sup> For 10 seconds

#### **■** Electro-optical Characteristics

(Ta=0 to 70°C unless otherwise specified)

	Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
*6	Current transfer ratio	CTR	I <sub>F</sub> =1.6mA, V <sub>O</sub> =0.4V, V <sub>CC</sub> =4.5V	300	1 600	-	%
	Logic (0) output voltage	$V_{OL}$	I <sub>0</sub> =4.8mA, V <sub>CC</sub> =4.5V, I <sub>F</sub> =1.6mA	-	0.1	0.4	V
	Logic (1) output current	Іон	$I_F=0$ , $V_{CC}=V_O=7V$	_	0.1	250	μΑ
	Logic (0) supply current	I <sub>CCL</sub>	I <sub>F</sub> =1.6mA, V <sub>CC</sub> =5V, V <sub>O</sub> =open	-	0.5	-	mA
	Logic (1) supply current	$I_{CCH}$	I <sub>F</sub> =0, V <sub>CC</sub> =5V, V <sub>O</sub> =open	-	10	-	nA
	Input forward voltage	$V_{\rm F}$	I <sub>F</sub> =1.6mA, Ta=25°C	-	1.5	1.7	V
	Input forward voltage temperature coefficient	*7	I <sub>F</sub> =1.6mA	_	-1.9	_	mV/°C
	Input reverse voltage	BV <sub>R</sub>	I <sub>R</sub> =10μA, Ta=25°C	5.0	_	-	V
	Input capacitance	Cin	V <sub>F</sub> =0, f=1MHz	_	60	-	pF
*8	Leak current (input-output)	I <sub>I-O</sub>	Ta=25°C, 45%RH, t=5s V <sub>I-O</sub> =3kV DC	_	-	1.0	μΑ
*8	Isolation resistance (input-output)	R <sub>I-O</sub>	V <sub>I-O</sub> =500V DC	_	1012	-	Ω
*8	Capacitance (input-output)	C <sub>I-O</sub>	f=1MHz	_	0.6	-	pF

<sup>\*6</sup> Current transfer ratio is the ratio of input current and output current expressed in %.

#### **■** Switching Characteristics

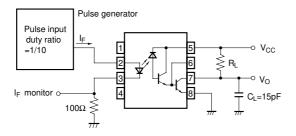
 $(Ta=25^{\circ}C, V_{CC}=5V)$ 

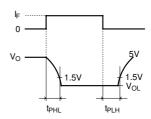
Note) Type value : at Ta=25°C

Parameter		Symbol	Conditions	MIN.	TYP.	MAX.	Unit
*9	Propagation delay time Output $(1) \rightarrow (0)$	t <sub>PHL</sub>	$ \begin{array}{l} I_F = 1.6 mA \\ R_L = 2.2 k\Omega \end{array} $	-	2	10	μs
*9	Propagation delay time Output $(0) \rightarrow (1)$	t <sub>PLH</sub>	$ I_F = 1.6 mA  R_L = 2.2 k\Omega $	_	7	35	μs
*10 *11	Instantaneous common mode rejection voltage " output (1) "	СМн	$ \begin{array}{c} I_F = 0, \ V_{CM} = 10 V_{P-P} \\ R_L = 2.2 k \Omega \end{array} $	_	500	_	V/µs
*10 *11	Instantaneous common mode rejection voltage " output (0) "	CML	$ \begin{array}{c} I_F\!=\!1.6mA,\ V_{CM}\!=\!10V_{P\text{-}P} \\ R_L=\!2.2k\Omega \end{array} $	_	-500	ı	V/µs

<sup>\*10</sup> Instantaneous common mode rejection voltage " output (1) " represents a common mode voltage variation that can hold the output above (1) level ( $V_0 > 2.0V$ ) Instantaneous common mode rejection voltage " output (0) " represents a common mode voltage variation that can hold the output above (0) level ( $V_0$ <0.8V)

#### \*9 Test Circuit for Propagation Delay Time

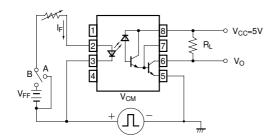




<sup>\*7</sup>  $\Delta V_F / \Delta T_a$ 

<sup>\*8</sup> Measured as 2-pin element (Short 1, 2, 3, 4 and 5, 6, 7, 8)

#### \*11 Test Circuit for Instantaneous Common Mode Rejection Voltage



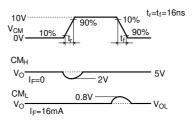


Fig. 1 Forward Current vs.
Ambient Temperature

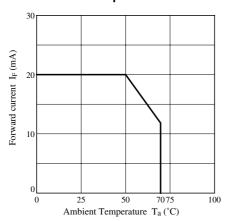


Fig. 3 Forward Current vs. Forward Voltage

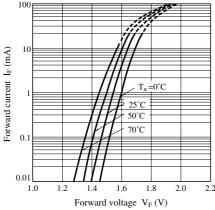


Fig. 2 Power Dissipation vs. Ambient Temperature

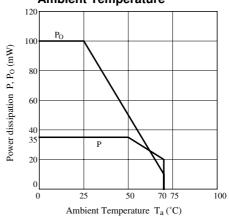
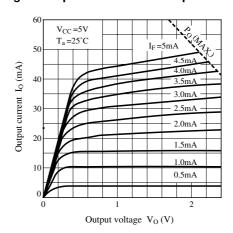


Fig. 4 Output Current vs. Output Voltage



SHARP 6N138

Fig. 5 Current Transfer Ratio vs. Forward Current

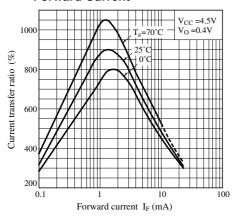


Fig. 7-a Propagation Delay Time vs. Ambient Temperature

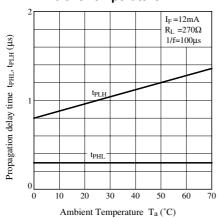


Fig. 8 Rise Time, Fall Time vs. Load Resistance

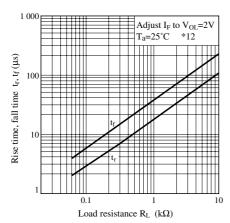


Fig. 6 Output Current vs. Forward Current

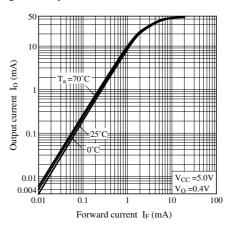


Fig. 7-b Propagation Delay Time vs. Ambient Temperature

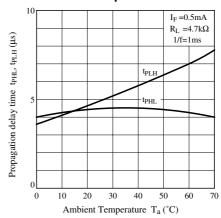
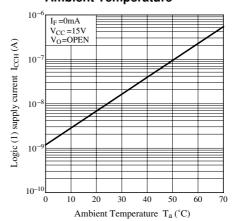
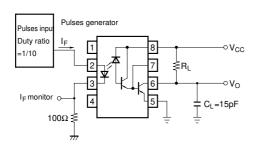
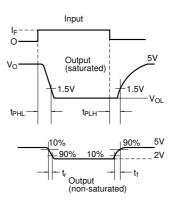


Fig. 9 Logic (1) Supply Current vs. Ambient Temperature



#### \*12 Test Circuit for Rise Time, Fall Time vs. Load Resistance





#### ■ Precaution for use

- (1) It is recommended that a by-pass capacitor of more than  $0.01\mu F$  be added between  $V_{CC}$  and GND near the device in order to stabilize power supply line.
- (2) Transistor of detector side in bipolar configuration is apt to be affected by static electricity for its minute design. When handling them, general counterplan against static electricity should be taken to avoid breakdown of devices or degradation of characteristics.

#### NOTICE

- •The circuit application examples in this publication are provided to explain representative applications of SHARP devices and are not intended to guarantee any circuit design or license any intellectual property rights. SHARP takes no responsibility for any problems related to any intellectual property right of a third party resulting from the use of SHARP's devices.
- •Contact SHARP in order to obtain the latest device specification sheets before using any SHARP device. SHARP reserves the right to make changes in the specifications, characteristics, data, materials, structure, and other contents described herein at any time without notice in order to improve design or reliability. Manufacturing locations are also subject to change without notice.
- Observe the following points when using any devices in this publication. SHARP takes no responsibility for damage caused by improper use of the devices which does not meet the conditions and absolute maximum ratings to be used specified in the relevant specification sheet nor meet the following conditions:
  - (i) The devices in this publication are designed for use in general electronic equipment designs such as:
  - Personal computers
  - Office automation equipment
- Telecommunication equipment [terminal]
- Test and measurement equipment
- Industrial control
- Audio visual equipment
- Consumer electronics
- (ii) Measures such as fail-safe function and redundant design should be taken to ensure reliability and safety when SHARP devices are used for or in connection with equipment that requires higher reliability such as:
- Transportation control and safety equipment (i.e., aircraft, trains, automobiles, etc.)
- Traffic signals
- Gas leakage sensor breakers
- Alarm equipment
- Various safety devices, etc.
- (iii) SHARP devices shall not be used for or in connection with equipment that requires an extremely high level of reliability and safety such as:
- Space applications
- Telecommunication equipment [trunk lines]
- Nuclear power control equipment
- Medical and other life support equipment (e.g., scuba).
- •Contact a SHARP representative in advance when intending to use SHARP devices for any "specific" applications other than those recommended by SHARP or when it is unclear which category mentioned above controls the intended use.
- •If the SHARP devices listed in this publication fall within the scope of strategic products described in the Foreign Exchange and Foreign Trade Control Law of Japan, it is necessary to obtain approval to export such SHARP devices.
- •This publication is the proprietary product of SHARP and is copyrighted, with all rights reserved. Under the copyright laws, no part of this publication may be reproduced or transmitted in any form or by any means, electronic or mechanical, for any purpose, in whole or in part, without the express written permission of SHARP. Express written permission is also required before any use of this publication may be made by a third party.
- Contact and consult with a SHARP representative if there are any questions about the contents of this
  publication.